Application No. 10/562,265

Attorney Docket No. 283485US0PCT

Response to Official Action dated July 27, 2009

AMENDMENTS TO THE CLAIMS

Please cancel claim 9, and amend claim 8, as follows:

Claims 1-7 (Cancelled).

Claim 8 (Currently Amended) A method for growing a thin bipolar gallium nitride

film on a sapphire substrate, said method comprising:

subjecting the sapphire substrate having arranged on a surface thereof a Ga face and a

N face to H₂ cleaning to grow the Ga face in a (+c) direction; and

treating the sapphire substrate, which has been subjected to H₂ cleaning, with a nitric

acid solution having a nitric acid concentration of 6-63 % to grow the N face in a (-c)

direction, wherein said treating is carried out at a temperature of 40°C for a period of θ

minutes 10 seconds to 10 minutes,

to thereby produce whereby the thin bipolar gallium nitride film having a Ga face (+c)

and a N face (-c) [[is]] grown on the sapphire substrate.

Claim 9 (Cancelled).

Claim 10 (Previously Presented) The method according to claim 8, wherein said

method further comprises:

exposing the sapphire substrate to air before growing the thin bipolar gallium nitride

film on the sapphire substrate.

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Claim 11 (Previously Presented) The method according to claim 8, wherein said

method further comprises, after said subjecting and before said treating:

forming a mask on the sapphire substrate, whereby patterned regions having different

polarities are formed in the thin bipolar gallium nitride film.

Claim 12 (Previously Presented) The method according to claim 11, wherein the

mask is formed from a photoresist.

Claim 13 (Previously Presented) The method according to claim 8, wherein the

sapphire substrate is a c face sapphire (Al₂O₃) substrate.

Claim 14 (Withdrawn) A thin bipolar gallium nitride film device manufactured by

the method according to claim 8.

Claim 15 (Withdrawn) The thin bipolar gallium nitride film device according to

claim 14, wherein the sapphire substrate is a c face sapphire (Al₂O₃) substrate.

Claim 16 (Withdrawn) The thin bipolar gallium nitride film device according to

claim 14 comprising a separated element.

Claim 17 (Withdrawn) The thin bipolar gallium nitride film device according to

claim 14 having a periodically patterned surface.

Claim 18 (Withdrawn) The thin bipolar gallium nitride film device according to

claim 14 comprising a separated element and having a periodically patterned surface.

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